PROGRAM

November 15 (Sunday)

16:00 – 19:00	Registration
18:00 – 20:00	Welcome (Mixer)

November 16 (Monday morning)

8:50 – 9:00	Opening	
9:00 – 9:35	**Session A:** J. O'Connor (Chair)	**After silicon: structure and composition of high-k materials on novel substrates** (Invited) T. Gustafsson
9:35 – 10:10		**Beyond hafnia** (Invited) M. Copel
10:10 – 10:30		**The analysis of ultra-thin films with HRBS-30** B. Brijs, K. Kimura, H. Bender, W. Vandervorst
10:30 – 11:00	Coffee break	
11:00 – 11:35	**Session B:** T. Gustafsson (Chair)	**Interface structures of metal oxide dielectrics and semiconductor nanocrystals** (Invited) L. Goncharova, E.G. Barbagiovanni, T. Gustafsson
11:35 – 12:10		**MEIS depth profiling of high-κ dielectrics for sub-45nm node CMOS applications** (Invited) P.R. Chalker, M. Werner, T.C.Q. Noakes, P. Bailey
12:10 – 12:30		**Extremely low energy SIMS for elemental quantification of ultrathin pedestal silicon-oxynitrides for high-κ devices** M. Py, J.P. Barnes, O. Renault, F. Martin, R. Gassilloud
12:30 – 14:00	Lunch	

November 16 (Monday afternoon)

14:00 – 14:35	**Session C:** P. Woodruff (Chair)	**High resolution medium energy ion scattering analysis for the quantitative depth profiling of ultra thin high–κ Hf based films** (Invited) J. van den Berg, M.A. Reading, D.G. Armour, P. Bailey, T. Noakes, T. Conard, S. De Gendt
14:35 – 15:10		**Surface and interface analysis with MEIS and LEEM/PEEM** (Invited) T. Koshikawa
15:10 – 15:30		**2-D analysis of hydrogen and oxygen maps on ion-implanted P and As in SiO_2 films** K. Ueda
15:30 – 16:00	Coffee break	
16:00 – 16:35	**Session D:** S. Nakagawa (Chair)	**Trajectroy-dependent energy loss in MEIS from crystalline surfaces** (Invited) A. Hentz, D.P. Woodruff, P.L. Grande, G. Schiwietz
16:35 – 17:10		**Electronic energy-loss at small impact parameters – backscattering of H and He at intermediate velocities** (Invited) G. Schiwietz, P.L. Grande
17:10 – 17:30		**Characterization of nanoparticles through medium-energy ion scattering (MEIS): The influence of the asymmetrical lineshape** M.A. Sortica, P.L. Grande, G. Machado, L. Miotti
17:30 – 17:50		**The shower approach in the simulation of ion scattering from solids** V.A. Khodyrev, R. Andrzejewski, D.O. Boerma, J.E. Prieto
18:30 – 20:30	Dinner	

November 17 (Tuesday morning)

8:45 – 9:20	**Session E:** T. Kaneko (Chair)	**Classical and quantum rainbow scattering: interaction potentials and structure of surfaces** (Invited) H. Winter, J. Seifert, M. Busch, S. Wethekam, A. Schüller
9:20 – 9:55		**Electronic interactions of slow ions** (Invited) P. Bauer, S.N. Markin, D. Primetzhofer, M. Spitz
9:55 – 10:15		**Energy-loss straggling of helium projectiles at low kinetic energies** G. Anderson
10:15 – 10:35		**Determination of thickness of thin films from grazing scattering experiments** I.K. Gainullin, D.K. Shestakov
10:35 – 11:00	Coffee break	
11:00 – 11:35	**Session F:** M. Copel (Chair)	**High resolution depth profiling by laser assisted 3D atom probe** (Invited) T. Ohkubo, Y.M. Chen, M. Kodzuka, F. Li, K. Hono
11:35 – 11:55		**Laser-assisted three-dimensional atom probe analysis of dopant distribution at NiSi/Si Schottky junction** T. Kinno, T. Ohkubo, Y. Nishi, T. Yamauchi, T. Marukame, K. Kato, M. Tomita, S. Takeno, K. Hono
11:55 – 12:15		**Probing local adatom kinetics above a single surface site in the field ion microscope using a pulse counting analysis of field-ions** A. Kobayashi, Y. Kamon, Y. Nakamura, K. Tanino, H. Kumagai
12:15 – 13:40	Lunch	

November 17 (Tuesday afternoon)

13:40 – 14:15	**Session G:** P. Bailey (Chair)	**Cooled growth: influencing the structure of rare earth silicides on silicon** (Invited) S.P. Tear, C. Eames, M. Reakes, T. Noakes, P. Bailey
14:15 – 14:50		**Growth and transition of Fe on Pt(001)** (Invited) D.J. O’Connor, D.A. McLaren, W. Allison, P.C. Dastoor, T.C.Q. Noakes
14:50 – 15:10		**Surface relaxation at a stepped surface: a MEIS study of Cu(410)-O and Cu(100)-O** D.C. Sheppard, A. Hentz, G.S. Parkinson, P.D. Quinn, M.A. Muñoz-Márquez, D.P. Woodruff
15:10 – 15:30		**A medium energy ion scattering study of Pd thin film growth on Cu(111)** T.C.Q. Noakes, P. Bailey, C.J. Howe, R.M. Wardle, T.P. Fleming, M.D. Cropper
15:30 – 16:00	Coffee break	
16:00 – 16:35	**Session H:** P.L. Grande (Chair)	**Narrow nuclear resonance profiling and stable isotopic tracing study of the diffusion and reaction of carbon monoxide molecules in thermal silica and at its interface with silicon** (Invited) I. Vickridge, M. D’Angelo, C.D. Cavellin, J.-J. Ganem, I. Trimaille, Y. Hoshino
16:35 – 16:55		**Application of SiN membrane to hydrogen depth profiling in atmosphere by NRA via $^{1}H(^{15}N,\alpha\gamma)^{12}C$** H. Yonemura, D. Sekiba, Y. Kitaoka, T. Narusawa, T. Ito, Y. Iwamura, K. Fukutani
16:55 – 17:15		**Resonance depth profiles of Si/C/Si layers using narrow nuclear resonances of elastic proton backscattering $p + {}^{12}C$ and $p + {}^{28}Si$** M. Tosaki, K. Yasuda, R. Ishigami
18:00 – 20:00	**Poster Session:** (with Snack)	List of poster presentations is to be announced elsewhere.

November 18 (Wednesday)

8:45 – 9:20	**Session I:** S. Matsuyama (Chair)	**Quantitative analysis of bio-interfaces with MEIS** (Invited) D.W. Moon
9:20 – 9:55		**A production of nano-beam with tapered glass capillaries and its application to living cell surgery** (Invited) Y. Yamazaki
9:55 – 10:15		**Secondary ion mass spectrometry depth profiling of organic films with large Ar cluster ion beams** S. Ninomiya, K. Ichiki, H. Yamada, T. Seki, T. Aoki, J. Matsuo
10:15– 10:45	Coffee break	
10:45 – 11:20	**Session J:** L. Goncharova (Chair)	**Sputter neutral mass spectrometry of surfaces from the NASA genesis mission** (Invited) B.V. King, I.V. Veryovkin, C.E. Tripa, A.V. Zinovev, M.J. Pellin
11:20 – 11:55		**Implanted solar wind oxygen about 4.6 billion years ago** (Invited) H. Yurimoto, S. Itoh
12:00 –	Excursion (with Box Lunch) to Kiyomizu and Fushimi	
18:30 – 20:30	Banquet	

November 19 (Thursday)

8:45 – 9:20	**Session K:** P. Bauer (Chair)	**Elastic recoil detection in the medium energy regime** (Invited) P. Bailey, T. Noakes, C. Bonet, T. Wood
9:20 – 9:55		**Quantitative ion beam analysis of ultra thin films with magnetic spectrometers using heavy MeV ions** (Invited) M. Kosmata, R. Grötzschel, M. Vieluf, D. Hanf, F. Munnik, W. Möller
9:55 – 10:15		**Ordering effects in extreme high-resolution depth profiling with MeV ion beams** H.J. Whitlow, S.T. Nakagawa
10:15– 10:45	Coffee break	
10:45 – 11:20	**Session L:** H. Winter (Chair)	**Spin polarization induced in organic thin films on ferromagnetic substrates** (Invited) Y. Yamauchi, X. Sun, S. Entani, M. Kurahashi, T. Suzuki, Z.P. Wang
11:20 – 11:40		**The growth of an ordered Mn layer on the Si(111)-1×1–Ho surface studied using MEIS and STM** (Invited) M.B. Reakes, C. Eames, T.C.Q. Noakes, P. Bailey, S.P. Tear
11:40 – 12:00		**High-resolution Channeling/RBS depth profiling of Sn implanted Si** T.K. Chan, T. Osipowicz, A. Markwitz
12:00 – 12:10	Closing	
12:10 – or 12:30 –	Lunch or Post Conference Tour (with Box Lunch) to Mt. Hiei	